


<b>Search Notes</b>  	<b>Application/Control No.</b>  10756776	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA, KOICHIRO
	<b>Examiner</b>  Nguyen, Phillip	<b>Art Unit</b>  2828

SEARCHED			
Class	Subclass	Date	Examiner
372	9,21-22,29.014	9/11/07	PN

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search updated	8/10/07	PN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	see the search history printout	9/11/07	PN